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# **Door-Module Driver-IC**

The NCV7707/B is a powerful Driver–IC for automotive body control systems. The IC is designed to control several loads in the front door of a vehicle. The monolithic IC is able to control mirror functions like mirror positioning, heating and folding including the electro–chromic mirror feature. Besides two half–bridge outputs to control lock and safe–lock motors, the device features four high–side outputs to drive LEDs or incandescent bulbs (up to 10 W). To allow maximum flexibility, all lighting outputs can be PWM controlled thru PWM inputs (external signal source) or by an internal programmable PWM generator unit. The NCV7707/B is controlled thru a 24 bit SPI interface with in–frame response.

#### **Features**

- Operating Range from 5.5 V to 28 V
- Six High–Side and Six Low–Side Drivers Connected as Half–Bridges
  - 2x Half-bridges  $I_{load} = 0.75 \text{ A}$ ;  $R_{DS(on)} = 1.6 \Omega$  @ 25°C
  - 2x Half-Bridges  $I_{load} = 3 \text{ A}$ ;  $R_{DS(on)} = 300 \text{ m}\Omega$  @ 25°C
  - 2x Half-Bridges  $I_{load} = 6 \text{ A}$ ;  $R_{DS(on)} = 150 \text{ m}\Omega$  @ 25°C
- Four High-Side Lamp Drivers
  - 2x LED;  $I_{load} = 0.3 \text{ A}$ ;  $R_{DS(on)} = 1.4 \Omega @ 25^{\circ}\text{C}$
  - 2x 10 W; configurable as LED Driver;  $I_{load} = 2.5 \text{ A}$ ;  $R_{DS(on)} = 300 \text{ m}\Omega @ 25^{\circ}\text{C}$
- One High–Side Driver for Mirror Heating;  $I_{load} = 6 \text{ A}$ ;  $R_{DS(on)} = 100 \text{ m}\Omega$  @ 25°C
- Electro Chromic Mirror Control
  - 1x 6–Bit Selectable Output Voltage Controller
  - 1x LS for EC Control; Iload = 0.75 A;  $R_{DS(on)} = 1.6 \Omega$  @ 25°C
- Independent PWM Functionality for All Outputs
- Integrated Programmable PWM Generator Unit for All Lamp Driver Outputs
- Programmable Soft-start Function to Drive Loads with Higher Inrush Currents as Current Limitation Value
- Multiplex Current Sense Analog Output for Advanced Load Monitoring
- Very Low Current Consumption in Standby Mode
- Charge Pump Output to Control an External Reverse Polarity Protection MOSFET
- 24-Bit SPI Interface for Output Control and Diagnostic
- Protection Against Short-circuit, Overvoltage and Overtemperature
- AEC-Q100 Qualified and PPAP Capable
- SSOP36-EP Power Package
- This is a Pb-Free Device

## **Typical Applications**

- De-centralized Door Electronic Systems
- Body Control Units (BCUs)

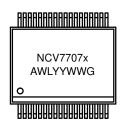


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### **MARKING DIAGRAM**



= blank or B

A = Assembly Location

WL = Wafer Lot

Y = Year

WW = Work Week

= Pb-Free Package

## **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NCV7707DQR2G	SSOP36-EP (Pb-Free)	1500 / Tape & Reel
NCV7707DQBR2G	SSOP36-EP (Pb-Free)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

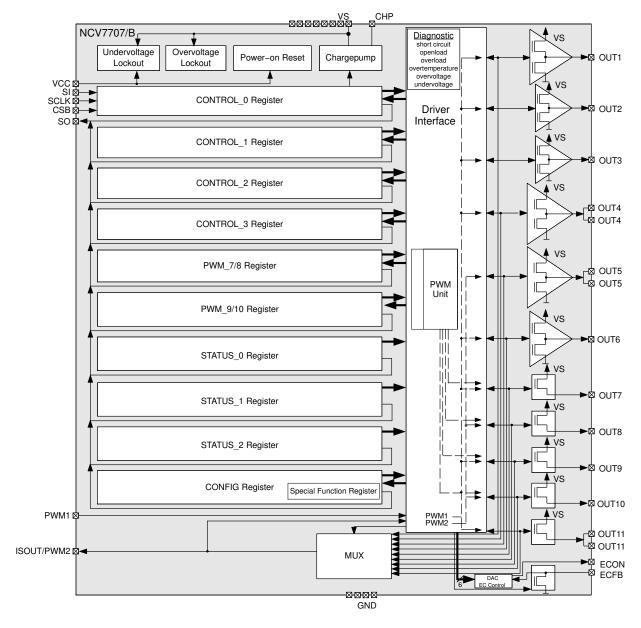


Figure 1. Block Diagram

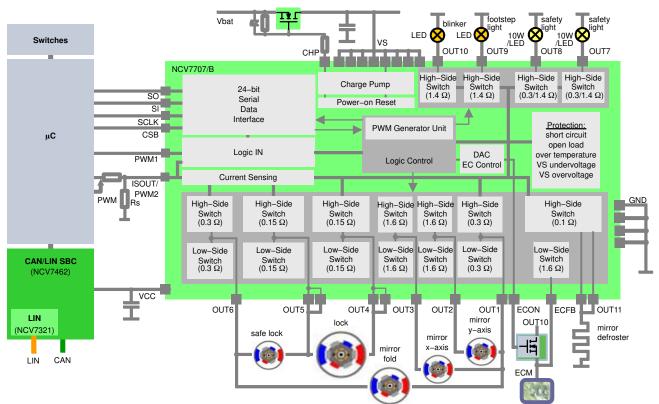


Figure 2. Application Diagram

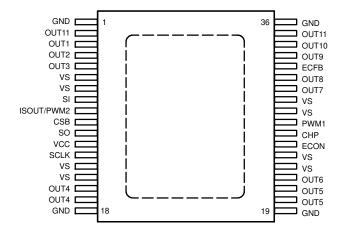


Figure 3. Pin Connections (Top View)

# PIN FUNCTION DESCRIPTION

Pin No.	Pin Name	Pin Type	Description
1	GND	Ground	Ground Supply (all GND pins have to be connected externally)
2	OUT11	HS driver Output	Heater Output (has to be connected externally to pin 35)
3	OUT1	Half bridge driver Output	Mirror common Output
4	OUT2	Half bridge driver Output	Mirror x/y control Output
5	OUT3	Half bridge driver Output	Mirror x/y control Output
6	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
7	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
8	SI	Digital Input	SPI interface Serial Data Input
9	ISOUT / PWM2	Digital Input / Analog Output	PWM control Input / Current Sense Output. This pin is a bidirectional pin. Depending on the selected multiplexer bits, an image of the instant current of the corresponding HS stage can be read out.  This pin can also be used as PWM control input pin for OUT5, OUT8 and OUT10.
10	CSB	Digital Input	SPI interface Chip Select
11	SO	Digital Output	SPI interface Serial Data Output
12	VCC	Supply	Logic Supply Input
13	SCLK	Digital Input	SPI interface Shift Clock
14	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
15	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
16	OUT4	Half bridge driver Output	Door Lock Output (has to be connected externally to pin 17)
17	OUT4	Half bridge driver Output	Door Lock Output (has to be connected externally to pin 16)
18	GND	Ground	Ground Supply (all GND pins have to be connected externally)
19	GND	Ground	Ground Supply (all GND pins have to be connected externally)
20	OUT5	Half bridge driver Output	Door Lock Output (has to be connected externally to pin 21)
21	OUT5	Half bridge driver Output	Door Lock Output (has to be connected externally to pin 20)
22	OUT6	Half bridge driver Output	Safe-Lock / Mirror Fold Output
23	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
24	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
25	ECON	ECM driver Output	Electrochromic mirror control DAC output. If the Electrochrome feature is selected, this output controls an external Mosfet, otherwise it remains in high–impedance state.  If the electrochrome feature is not used in the application and not selected via SPI the pin can be connected to VS.
26	CHP	Analog Output	Reverse Polarity FET Control Output
27	PWM1	Digital Input	PWM control Input for OUT1–4, OUT6/7, OUT9, OUT11
28	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
29	VS	Supply	Battery Supply Input (all VS pins have to be connected externally)
30	OUT7	HS driver Output	LED / Bulb Output
31	OUT8	HS driver Output	LED / Bulb Output
32	ECFB	ECM Input / Output	Electrochromic Mirror Feedback Input, Fast discharge transistor Output
33	OUT9	HS driver Output	LED Output
34	OUT10	HS driver Output	LED Output
35	OUT11	HS driver Output	Heater Output (has to be connected externally to pin 2)
36	GND	Ground	Ground Supply (all GND pins have to be connected externally)
	Heat slug	Ground	Substrate; Heat slug has to be connected to all GND pins

### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Rating	Min	Max	Unit
Vs	Power supply voltage  - Continuous supply voltage  - Transient supply voltage (t < 500 ms, "clamped load dump")	-0.3 -0.3	28 40	V
V <sub>CC</sub>	Logic supply	-0.3	5.5	٧
Vdig	DC voltage at all logic pins (SO, SI, SCLK, CSB, PWM1)	-0.3	V <sub>CC</sub> + 0.3	٧
Visout/pwm2	Current monitor output / PWM2 logic input	-0.3	V <sub>CC</sub> + 0.3	٧
Vchp	Charge pump output (the most stringent value is applied)	–25 Vs – 25	40 Vs + 15	V
Voutx, Vecon, Vecfb	Static output voltage (OUT1-11, ECON, ECFB)	-0.3	Vs + 0.3	V
lout1/6	OUT1/6 Output current	-5	5	Α
lout2/3	OUT2/3 Output current	-1.25	1.25	Α
lout4/5	OUT4/5 Output current	-10	10	Α
lout7/8	OUT7/8 Output current	-5	5	Α
lout9/10	OUT9/10 Output current	-1.25	1.25	Α
lout11	OUT11 Output current	-10	10	Α
lout_ecfb	ECFB Output current		1.25	Α
ESD_HBM	ESD Voltage, Human Body Model (HBM); (100 pF, 1500 Ω) (Note 1)  – All pins  – Output pins OUT1–6 and ECFB to GND (all unzapped pins grounded)	-2 -4	2 4	kV
ESD_CDM	ESD according to CDM (Charge Device Model) (Note 1)  – All pins  – Corner pins	-500 -750	500 750	V
T <sub>J</sub>	Operating junction temperature range	-40	150	°C
Tstg	Storage temperature range	-55	150	°C
MSL	Moisture sensitivity level (Note 2)	MS	SL3	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. This device series incorporates ESD protection and is tested by the following methods:
ESD Human Body Model tested per AEC-Q100-002 (EIA/JESD22-A114)
ESD Charge Device Model tested per EIA/JES D22/C101, Field Induced Charge Model

- 2. For soldering information, please refer to our Soldering and Mounting Techniques Reference Manual, SOLDERRM/D

## THERMAL CHARACTERISTICS

Symbol	Symbol Rating		Unit		
$R_{ heta JC}$	Thermal Characteristics, SSOP36–EP Thermal Resistance, Junction–to–Case				
R <sub>θJA</sub>	Thermal Characteristics, SSOP36–EP, 1–layer PCB Thermal Resistance, Junction–to–Air (Note 3)	42	°C/W		
R <sub>θJA</sub>	Thermal Characteristics, SSOP36–EP, 4–layer PCB Thermal Resistance, Junction–to–Air (Note 4)	19.5	°C/W		

- 3. Values based on PCB of 76.2 x 114.3 mm, 72 µm copper thickness, 20 % copper area coverage and FR4 PCB substrate.
- Values based on PCB of 76.2 x 114.3 mm, 72 / 36 μm copper thickness (signal layers / internal planes), 20 / 90 % copper area coverage (signal layers / internal planes) and FR4 PCB substrate.

# **ELECTRICAL CHARACTERISTICS**

 $4.5~V < V_{CC} < 5.25~V,~8~V < Vs < 18~V,~-40^{\circ}C < T_{J} < 150^{\circ}C;$  unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
SUPPLY						
Vs	Supply voltage	Functional (see V <sub>UV_VS</sub> / V <sub>OV_VS</sub> ) Parameter specification	5.5 8		28 18	V
Is(standby)	Supply Current (VS), Standby mode	$ \begin{array}{l} \text{Standby mode,} \\ \text{VS} = 16 \text{ V}, 0 \text{ V} \leq \text{V}_{CC} \leq 5.25 \text{ V}, \\ \text{CSB} = \text{V}_{CC}, \text{OUTx/ECx} = \text{floating,} \\ \text{SI} = \text{SCLK} = 0 \text{ V}, \text{T}_{J} < 85^{\circ}\text{C} \\ (\text{T}_{J} = 150^{\circ}\text{C}) \end{array} $		3.5 (9)	12 (25)	μΑ
Is(active)	Supply current (VS), Active mode	Active mode, VS = 16 V, OUTx/ECx = floating		8	20	mA
I <sub>CC</sub> (standby)	Supply Current (VCC), Standby mode	$\label{eq:controller} \begin{split} & \text{Standby mode,} \\ & \text{V}_{CC} = 5.25 \text{ V,} \\ & \text{SI} = \text{SCLK} = 0 \text{ V, T}_{J} < 85^{\circ}\text{C} \\ & (\text{T}_{J} = 150^{\circ}\text{C}) \end{split}$		4.5 (15)	6 (50)	μΑ
I <sub>CC</sub> (active)	Supply current (VCC), Active mode	Active mode, VS = 16 V, OUTx/ECx = floating		6.5	8.4	mA
I(standby)	Total Standby mode supply current (Is + I <sub>CC</sub> )	Standby mode, VS = 16 V, T <sub>J</sub> < 85°C, CSB = V <sub>CC</sub> , OUTx/ECx = floating		8	18	μΑ
OVERVOLTAGE A	ND UNDERVOLTAGE DETEC	CTION				
Vuv_vs(on)	VS Undervoltage detection	VS increasing	5.6		6.2	V
Vuv_vs(off)		VS decreasing	5.2		5.8	V
Vuv_vs(hys)	VS Undervoltage hysteresis	Vuv_vs(on) – Vuv_vs(off)		0.65		V
Vov_vs(off)	VO 0	VS increasing	20		24.5	V
Vov_vs(on)	VS Overvoltage detection	VS decreasing	19		23.5	V
Vov_vs(hys)	VS Overvoltage hysteresis	Vov_vs(off) - Vov_vs(on)		2		V
Vuv_vcc(off)	VCC Undervoltage	V <sub>CC</sub> increasing			2.9	V
Vuv_vcc(on)	detection	V <sub>CC</sub> decreasing	2			V
Vuv_vcc(hys)	VCC Undervoltage hysteresis	$V_{uv\_VCC(off)} - V_{uv\_VCC(on)}$		0.11		٧
td_uvov	VS Undervoltage / Overvoltage filter time	Time to set the power supply fail bit UOV_OC in the Global Status Byte	6		100	μS
CHARGE PUMP C	OUTPUT CHP					
Vchp8	Chargepump Output Voltage	Vs = 8 V, lchp = -60 μA	Vs + 6	Vs + 9.5	Vs + 13	V
Vchp10	Chargepump Output Voltage	Vs = 10 V, Ichp = -80 μA	Vs + 8	Vs + 11	Vs + 13	V
Vchp12	Chargepump Output Voltage	VS > 12 V, lchp = -100 μA	Vs + 9.5	Vs + 11	Vs + 13	V
Ichp	Chargepump Output current	VS = 13.5 V, Vchp = Vs + 10 V	-750		-95	μΑ

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
MIRROR COMMON	OUTPUT (X/Y, FOLD) OUT1			•		
Dan aut	On manietamen IIC am I C	$T_J = 25^{\circ}C$ , lout1 = ±1.5 A		0.3		
Ron_out1	On-resistance HS or LS	$T_J = 125$ °C, lout1 = ±1.5 A			0.6	Ω
loc1_hs	Overcurrent threshold HS		<b>-</b> 5		-3	Α
loc1_ls	Overcurrent threshold LS		3		5	Α
Vlim1	Vds voltage limitation HS or LS		2		3	V
luld1_hs	Underload detection threshold HS		-80		-5	mA
luld1_ls	Underload detection threshold LS		10		80	mA
td_HS1(on)	Output delay time, HS Driver on	Time from CSB going high to		2.5	12	μs
td_HS1(off)	Output delay time, HS Driver off	$V(OUT1) = 0.1 \cdot Vs / 0.9 \cdot Vs (on/off)$		3	12	μs
td_LS1(on)	Output delay time, LS Driver on	Time from CSB going low to		1	12	μs
td_LS1(off)	Output delay time, LS Driver off	$V(OUT1) = 0.9 \cdot Vs / 0.1 \cdot Vs (on/off)$		1.5	12	μs
tdLH1	Cross conduction protection time, low-to-high transition including LS slew-rate			0.5	22	μs
tdHL1	Cross conduction protection time, high-to-low transition including HS slew-rate			5.5	22	μs
lleak_act_hs1	Output HS leakage current, Active mode	V(OUT1) = 0 V	-40	-16		μА
lleak_act_ls1	Output pull-down current, Active mode	V(OUT1) = VS		100	160	μΑ
lleak_stdby_hs1	Output HS leakage current, Standby mode	V(OUT1) = 0 V	<b>-</b> 5			μΑ
lleak_stdby_ls1	Output pull-down current, Standby mode	$V(OUT1) = VS, T_J \ge 25^{\circ}C$ $V(OUT1) = VS, T_J < 25^{\circ}C$		80	120 175	μΑ
td_uld1	Underload blanking delay		430		3000	μS
td_old1	Overload shutdown blanking delay		5		25	μs
frec1L	Recovery frequency, slow recovery mode	CONTROL_3.OCRF = 0	1		4	kHz
frec1H	Recovery frequency, fast recovery mode	CONTROL_3.OCRF = 1	2		6	kHz
dVout1	Slew rate of HS driver	Vs = 13.5 V, Rload = 16 $\Omega$ to GND	1	2	3	V/μs

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
MIRROR X/Y POSIT	TIONING OUTPUTS OUT2, O	UT3				
Dam auto o	On masiatanaa 110 au 10	$T_J = 25^{\circ}C$ , lout2,3 = ±0.5 A		1.6		Ω
Ron_out2,3	On–resistance HS or LS	$T_J = 125$ °C, lout2,3 = ±0.5 A			3	Ω
loc2,3_hs	Overcurrent threshold HS		-1.25		-0.75	Α
loc2,3_ls	Overcurrent threshold LS		0.75		1.25	Α
Vlim2,3	Vds voltage limitation HS or LS		2		3	V
luld2,3_hs	Underload detection threshold HS		-30	-20	-10	mA
luld2,3_ls	Underload detection threshold LS		10	20	30	mA
td_HS2,3(on)	Output delay time, HS Driver on	Time from CSB going high to		2.5	12	μs
td_HS2,3(off)	Output delay time, HS Driver off	V(OUT2,3) = 0.1·Vs / 0.9·Vs (on/ off)		3	12	μs
td_LS2,3(on)	Output delay time, LS Driver on	Time from CSB going low to		1	12	μs
td_LS2,3(off)	Output delay time, LS Driver off	$V(OUT2,3) = 0.9 \cdot Vs / 0.1 \cdot Vs (on/off)$		1	12	μs
tdLH2,3	Cross conduction protection time, low-to-high transition including LS slew-rate			0.5	22	μs
tdHL2,3	Cross conduction protection time, high-to-low transition including HS slew-rate			5.5	22	μs
lleak_act_hs2,3	Output HS leakage current, Active mode	V(OUT2,3) = 0 V	-40	-16		μΑ
lleak_act_ls2,3	Output pull-down current, Active mode	V(OUT2,3) = VS		100	160	μΑ
Ileak_stdby_hs2,3	Output HS leakage current, Standby mode	V(OUT2,3) = 0 V	-5			μΑ
lleak_stdby_ls2,3	Output pull-down current, Standby mode	$V(OUT2,3) = VS, T_J \ge 25^{\circ}C$ $V(OUT2,3) = VS, T_J < 25^{\circ}C$		80	120 175	μ <b>Α</b> μ <b>Α</b>
td_uld2,3	Underload blanking delay		430		3000	μS
td_old2,3	Overload shutdown blanking delay		10		100	μs
frec2,3L	Recovery frequency, slow recovery mode	CONTROL_3.OCRF = 0	1		4	kHz
frec2,3H	Recovery frequency, fast recovery mode	CONTROL_3.OCRF = 1	2		6	kHz
dVout2,3	Slew rate of HS driver	Vs = 13.5 V, Rload = 64 $\Omega$ to GND	1	2	3	V/µs

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
DOOR LOCK OUTP	PUTS OUT4, OUT5					
5		$T_J = 25^{\circ}C$ , lout4,5 = ±3 A		0.15		Ω
Ron_out4,5	On-resistance HS or LS	T <sub>J</sub> = 125°C, lout4,5 = ±3 A			0.3	Ω
loc4,5_hs	Overcurrent threshold HS	T <sub>J</sub> > 0°C	-10		-6	Α
loc4,5_hs_ct	Overcurrent threshold HS	$T_J \leq 0$ °C	-10		-5.75	Α
loc4,5_ls	Overcurrent threshold LS		6		10	Α
Vlim4,5	Vds voltage limitation HS or LS		2		3	V
luld4,5_hs	Underload detection threshold HS		-300		-60	mA
luld4,5_ls	Underload detection threshold LS		60		300	mA
td_HS4,5 (on)	Output delay time, HS Driver on	Time from CSB going high to V(OUT4.5) = 0.1·Vs / 0.9·Vs (on/		2.5	12	μs
td_HS4,5 (off)	Output delay time, HS Driver off	off)		3	12	μs
td_LS4,5 (on)	Output delay time, LS Driver on	Time from CSB going low to V(OUT4,5) = 0.9·Vs / 0.1·Vs (on/		1	12	μs
td_LS4,5 (off)	Output delay time, LS Driver off	off)		1.5	12	μs
tdLH4,5	Cross conduction protection time, low-to-high transition including LS slew-rate			0.5	22	μs
tdHL4,5	Cross conduction protection time, high-to-low transition including HS slew-rate			5.5	22	μs
lleak_act_hs4,5	Output HS leakage current, Active mode	V(OUT4,5) = 0 V	-40	-17		μΑ
lleak_act_ls4,5	Output pull-down current, Active mode	V(OUT4,5) = VS		100	160	μΑ
Ileak_stdby_hs4,5	Output HS leakage current, Standby mode	V(OUT4,5) = 0 V	-5			μΑ
lleak_stdby_ls4,5	Output pull-down current, Standby mode	$V(OUT4,5) = VS, T_J \ge 25^{\circ}C$ $V(OUT4,5) = VS, T_J < 25^{\circ}C$		80	120 175	μ <b>Α</b> μ <b>Α</b>
td_uld4,5	Underload blanking delay		430		3000	μs
td_old4,5	Overload shutdown blanking delay		10		25	μs
frec4,5L	Recovery frequency, slow recovery mode	CONTROL_3.OCRF = 0	1		4	kHz
frec4,5H	Recovery frequency, fast recovery mode	CONTROL_3.OCRF = 1	2		6	kHz
dVout4,5	Slew rate of HS driver	Vs = 13.5 V, Rload = 4 $\Omega$ to GND	1	2	3	V/μs

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
SAFE LOCK, MIRR	OR FOLD OUTPUT OUT6					•
		$T_J = 25^{\circ}C$ , lout6 = ±1.5 A		0.3		
Ron_out6	On–resistance HS or LS	$T_J = 125$ °C, lout6 = ±1.5 A			0.6	Ω
loc6_hs	Overcurrent threshold HS		<b>-</b> 5		-3	Α
loc6_ls	Overcurrent threshold LS		3		5	Α
Vlim	Vds voltage limitation HS or LS		2		3	V
luld6_hs	Underload detection threshold HS		-80		<b>-</b> 5	mA
luld6_ls	Underload detection threshold LS		10		80	mA
td_HS6(on)	Output delay time, HS Driver on	Time from CSB going high to		2.5	12	μs
td_HS6(off)	Output delay time, HS Driver off	$V(OUT6) = 0.1 \cdot Vs / 0.9 \cdot Vs (on/off)$		3	12	μs
td_LS6(on)	Output delay time, LS Driver on	Time from CSB going low to		1	12	μs
td_LS6(off)	Output delay time, LS Driver off	V(OUT6) = 0.9·Vs / 0.1·Vs (on/off)		1.5	12	μs
tdLH6	Cross conduction protection time, low-to-high transition including LS slew-rate			0.5	22	μs
tdHL6	Cross conduction protection time, high-to-low transition including HS slew-rate			5.5	22	μs
lleak_act_hs6	Output HS leakage current, Active mode	V(OUT6) = 0 V	-40	-16		μА
lleak_act_ls6	Output pull-down current, Active mode	V(OUT6) = VS		100	160	μΑ
Ileak_stdby_hs6	Output pull-down current, Standby mode	V(OUT6) = 0 V	-5			μА
Ileak_stdby_ls6	Output LS leakage current, Standby mode	$V(OUT6) = VS, T_J \ge 25^{\circ}C$ $V(OUT6) = VS, T_J < 25^{\circ}C$		80	120 175	μ <b>Α</b> μ <b>Α</b>
td_uld6	Underload blanking delay		430		3000	μS
td_old6	Overload shutdown blanking delay		5		25	μs
frec6L	Recovery frequency, slow recovery mode	CONTROL_3.OCRF = 0	1		4	kHz
frec6H	Recovery frequency, fast recovery mode	CONTROL_3.OCRF = 1	2		6	kHz
dVout6	Slew rate of HS driver	Vs = 13.5 V, Rload = 16 $\Omega$ to GND	1	2	3	V/μs

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
BULB / LED DRIVE	R OUTPUTS OUT7, OUT8					
	On-resistance to supply,	T <sub>J</sub> = 25°C, lout7,8 = -1 A		0.3		
Ron_out7,8_ICB	HS switch, Bulb mode	T <sub>J</sub> = 125°C, lout7,8 = -1 A			0.6	Ω
	On-resistance to supply,	$T_J = 25^{\circ}C$ , lout7,8 = -0.2 A		1.4		_
Ron_out7,8_LED	HS switch, LED mode	$T_J = 125^{\circ}C$ , lout7,8 = -0.2 A			3	Ω
Ilim7,8_ICB	Output current limitation to GND, Bulb mode		-3.7		-2.5	Α
llim7,8_LED	Overcurrent threshold, LED mode		-1.1		-0.5	Α
luld7,8_ICB	Underload detection threshold, Bulb mode		-60		<b>–</b> 5	mA
luld7,8_LED	Underload detection threshold, LED mode		-15		<b>-</b> 5	mA
td_OUT7,8_ICB(on)	Output delay time, Driver on, Bulb mode	Time from CSB going high to V(OUT7,8) = 0.1·Vs / 0.9·Vs (on/		15	48	
td_OUT7,8_ICB(off)	Output delay time, Driver off, Bulb mode	off); Rload = 16 $\Omega$		21	48	— μs
td_OUT7,8_LED(on)	Output delay time, Driver on, LED mode	Time from CSB going high to V(OUT7,8) = 0.1·Vs / 0.9·Vs (on/		15	48	
td_OUT7,8_LED(off)	Output delay time, Driver off, LED mode	off); Rload = 64 $\Omega$		21	48	μs
lleak_act7,8	Output leakage current, Active mode	V(OUT7,8) = 0 V	-15			μΑ
lleak_stdby7,8	Output leakage current, Standby mode	V(OUT7,8) = 0 V	<b>–</b> 5			μΑ
lleak_out_vs7,8	Output pull-down current	V(OUT7,8) = VS			1	mA
td_uld7,8	Underload blanking delay		430		3000	μs
td_old_ICB7,8	Overload shutdown blanking delay, Bulb mode		100		160	μs
td_old_LED7,8	Overload shutdown blanking delay, LED mode only		10		100	μs
frec7,8L	Recovery frequency, slow recovery mode recovery	CONTROL_3.OCRF = 0	1		2.1	kHz
frec7,8H	Recovery frequency, fast recovery mode (LED mode only)	CONTROL_3.OCRF = 1	2		6	kHz
dVout7,8_ICB	Slew rate, Bulb mode	Vs = 13.5 V, Rload = 16 Ω		0.2		V/μs
dVout7,8_LED	Slew rate, LED mode	Vs = 13.5 V, Rload = 64 Ω		0.2		V/μs
dVout7,8_ocr	Slew rate in overcurrent recovery mode	Vs = 13.5 V, Rload = 5 Ω	1	2	3	V/μs

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
LED DRIVER OUTP	UTS OUT9, OUT10					
D 10.10	On-resistance to supply,	T <sub>J</sub> = 25°C, lout9,10 = -0.2 A		1.4		Ω
Ron_out9,10	HS switch	T <sub>J</sub> = 125°C, lout9,10 = -0.2 A			3	Ω
loc9,10	Overcurrent threshold		-0.63		-0.38	Α
luld9,10	Underload detection threshold		-16		-4	mA
td_OUT(on)9,10	Output delay time, Driver on	Time from CSB going high to		18	48	
td_OUT(off)9,10	Output delay time, Driver off	V(OUT9,10) = 0.1·Vs / 0.9·Vs (on/ off)		23	48	μs
Ileak_act9,10	Output leakage current, Active mode	V(OUT9,10) = 0 V	-10			μΑ
lleak_stdby9,10	Output leakage current, Standby mode	V(OUT9,10) = 0 V	-5			μА
Ileak_out_vs9,10	Output pull-down current	V(OUT9,10) = VS			1	mA
td_uld9,10	Underload blanking delay		250		750	μs
td_old_OUT9,10	Overload shutdown blanking delay		10		100	μs
frec9,10L	Recovery frequency, slow recovery mode	CONTROL_3.OCRF = 0	1		4	kHz
frec9,10H	Recovery frequency, fast recovery mode	CONTROL_3.OCRF = 1	2		6	kHz
dVout9,10	Slew rate	Vs = 13.5 V, Rload = 64 Ω		0.2		V/μs
HEATER OUTPUT	DUT11			•		•
D 144	On-resistance to supply,	$T_J = 25^{\circ}C$ , lout11 = -3 A		0.1		Ω
Ron_out11	HS switch	$T_J = 125^{\circ}C$ , lout11 = -3 A			0.2	Ω
loc11	Overcurrent threshold		-10		-6.0	Α
luld11	Underload detection threshold		-300		-30	mA
td_OUT11(on)	Output delay time, Driver on	Time from CSB going high to		3	12	
td_OUT11(off)	Output delay time, Driver off	V(OUT11) = 0.1 · Vs / 0.9 · Vs (on/off)		3	12	μs
lleak_act11	Output leakage current, Active mode	V(OUT11) = 0 V	-10			μА
lleak_stdby11	Output leakage current, Standby mode	V(OUT11) = 0 V	-5			μΑ
lleak_out11_vs	Output pull-down current	V(OUT11) = VS			1	mA
td_uld11	Underload blanking delay		430		3000	μS
td_old_OUT11	Overload shutdown blanking delay		5		25	μS
frec11L	Recovery frequency, slow recovery mode	CONTROL_3.OCRF = 0	1		4	kHz
frec11H	Recovery frequency, fast recovery mode	CONTROL_3.OCRF = 1	2		6	kHz
dVout11	Slew rate	Vs = 13.5 V, Rload = 4 Ω	1	2	3	V/µs

# **ELECTRICAL CHARACTERISTICS** (continued)

 $4.5~V < V_{CC} < 5.25~V, 8~V < Vs < 18~V, -40 ^{\circ}C < T_{J} < 150 ^{\circ}C;$  unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
LECTROCHROMI	C MIRROR CONTROL (ECFI	B, ECON)		•		•
D (1	On-resistance to GND, LS	T <sub>J</sub> = 25°C, lecfb = 0.5 A		1.6		Ω
Ron_ecfb	switch	T <sub>J</sub> = 125°C, lecfb = 0.5 A			3	Ω
Ilim_ecfb_src	Output current limitation to GND	Vs = 13.5V, V <sub>CC</sub> = 5 V	0.75		1.25	Α
Vlim_ecfb	Vds voltage limitation	Output enabled	2		3	٧
luld_ecfb	Underload detection threshold	Vs = 13.5 V, V <sub>CC</sub> = 5 V	10	20	30	mA
td_ecfb(on)	Output delay time, LS Driver on	Vs = 13.5 V, V <sub>CC</sub> = 5 V, Rload = 64 Ω.		1	12	
td_ecfb(off)	Output delay time, LS Driver off	V(ECFB) = 0.9·VS / 0.1·VS (on /off)		2	12	<b>-</b> μs
lleak_ecfb_stdby	Output leakage current, LS	Vecfb = Vs, Standby mode	-15		15	μΑ
lleak_ecfb_act	off	Vecfb = Vs, Active mode	-10		10	μΑ
td_uld_ecfb	Underload blanking delay		430		3000	μS
td_old_ecfb	Overload shutdown blanking delay		10		100	μS
dVecfb/dt(on/off)	Slew rate of ECFB, LS switch	$Vs = 13.5 \text{ V}, V_{CC} = 5 \text{ V},$ Rload = 64 $\Omega$		5		V/μs
Vctrl_max	Maximum EC control	CONTROL_2.FSR = 1	1.4		1.6	V
_	voltage	CONTROL_2.FSR = 0	1.12		1.28	V
DNL	Differential non linearity	1 LSB = 23.8 mV	-1		1	LSB
dV_ecfb	Voltage deviation between target and ECFB	dV_ecfb = Vtarget – Vecfb, lecon < 1 μA gain offset	–5% –1 LSB		+5% +1 LSB	mV
dV_ecfb_lo	Difference voltage between target and ECFB sets flag if Vecfb is below target	dV_ecfb = Vtarget - Vecfb, Toggle bit STATUS_2.ECLO = 1		120		mV
dV_ecfb_hi	Difference voltage between target and ECFB sets flag if Vecfb is above target	dV_ecfb = Vtarget - Vecfb, Toggle bit STATUS_2.ECHI = 1		-120		mV
Vecon_min_hi	ECON output voltage	lecon = -10 μA	4.5		5.5	V
Vecon_max_lo	range	lecon = 10 μA	0		0.7	T *
	ECON output current	Vtarget > Vecfb + 500 mV, Vecfb = 3.5 V	-100		-10	μА
lecon	capability	Vtarget < Vecfb – 500 mV, Vecon = 1 V, Vtarget = 1 LSB, Vecfb = 0.5 V	10		100	μΑ
Recon_pd	Pull-down resistance at ECON in fast discharge mode	Vecon = 0.7 V, CONTROL_1.ECEN = 1, CONTROL_1.LSECFB = 1, CONTROL_1.DAC[5:0] = 0			5	kΩ
lq_econ	ECON quiescent current	Vecon = Vs, CONTROL_1.ECEN = 0			1	μΑ
t_disc	Auto-discharge pulse width	Config.LSPWM=1	240	300	360	ms
t_rec	Auto-discharge blanking time	Config.LSPWM=1	2.25	3	3.75	ms
Vthdisc_abs	PWM discharge threshold level V(ECON) (Note 5)	Config.LSPWM=1	350	400	450	mV
Vthdisc_diff	PWM discharge threshold level V(ECON) – V(ECFB) (Note 5)	Config.LSPWM=1	-50	0	50	mV

<sup>5.</sup> If V(ECON) < Vthdisc\_abs or V(ECON)-V(ECFB) < Vthdisc\_diff then ECON\_LOW =1; see description in paragraph Controller for Electro-chromic Glass

Symbol	Parameter	Parameter Test Conditions		Тур	Max	Unit
CURRENT SENSE	MONITOR OUTPUT ISOUT/F	PWM2				
Vis	Current Sense output functional voltage range	V <sub>CC</sub> = 5 V, Vs = 8–20 V	0		V <sub>CC</sub> – 1	V
	Current Sense output ratio OUT1/6 and 7/8 (low on–resistance bulb mode)			10000		
Kis	Current Sense output ratio OUT4/5	K = lout / lis,		9200		
(Note 6)	Current Sense output ratio OUT9/10 and 7/8 (high on–resistance LED mode)	$0 \text{ V} \leq \text{Vis} \leq 4 \text{ V}, \text{ V}_{CC} = 5 \text{ V}$		2000		
	Current Sense output ratio OUT11		4500		18000	
	Current Sense output accuracy OUT1/6	$\begin{array}{l} 0 \; V \; \leq \; Vis \; \leq \; 4 \; V,  V_{CC} \; = \; 5 \; V \\ lout1/6 \; = \; 1-1.6 \; A, \; T_J \; \geq \; 25^{\circ}C \\ lout1/6 \; = \; 1-1.6 \; A, \; T_J \; < \; 25^{\circ}C \\ lout1/6 \; = \; 0.5-1 \; A; \; 1.6-2.9 \; A \end{array}$	-10% - 2% FS -10% - 2% FS -22% - 2% FS		10% + 2% FS 15% + 2% FS 22% + 2% FS	
	Current Sense output accuracy OUT4/5	$\begin{array}{l} 0 \; V \; \leq \; Vis \; \leq \; 4 \; V,  V_{CC} \; = \; 5 \; V, \\ lout4/5 \; = \; 2.6 - 3.3 \; A,  T_J \; \geq \; 25^\circ C \\ lout4/5 \; = \; 2.6 - 3.3 \; A,  T_J \; < \; 25^\circ C \\ lout4/5 \; = \; 0.5 - 2.6 \; A; \; 3.3 - 5.9 \; A \end{array}$	-10% - 2% FS -10% - 2% FS -22% - 3% FS		10% + 2% FS 19% + 2% FS 22% + 3% FS	
lis,acc (Notes 7 and 8)	Current Sense output accuracy OUT7/8 (low on–resistance bulb mode)	$\begin{array}{l} 0 \; V \; \leq \; Vis \; \leq \; 4 \; V, \; V_{CC} = 5 \; V \\ lout7/8 = 0.6 - 0.7 \; A, \; T_J \; \geq \; 25^{\circ}C \\ lout7/8 = 0.6 - 0.7 \; A, \; T_J \; < \; 25^{\circ}C \\ lout7/8 = 0.5 - 0.6 \; A; \; 0.7 - 1.3 \; A \end{array}$	-10% - 2% FS -10% - 2% FS -20% - 2% FS		10% + 2% FS 18% + 2% FS 20% + 2% FS	
	Current Sense output accuracy OUT7/8 (high on-resistance LED mode)	$\begin{array}{l} 0~V \leq Vis \leq 4~V,  V_{CC} = 5~V \\ lout7/8 = 0.14 - 0.16~A,  T_{J} \geq 25^{\circ}C \\ lout7/8 = 0.14 - 0.16~A,  T_{J} < 25^{\circ}C \\ lout7/8 = 0.1 - 0.14~A;  0.16 - 0.3~A \end{array}$	-12%- 2% FS -12%- 2% FS -18% - 2% FS		12% + 2% FS 15% + 2% FS 18% + 2% FS	
	Current Sense output accuracy OUT9/10	$0 \text{ V} \leq \text{Vis} \leq 4 \text{ V}, \text{ V}_{CC} = 5 \text{ V} \\ \text{lout9/10} = 0.15 - 0.25 \text{ A} \\ \text{lout9/10} = 0.1 - 0.15 \text{ A}; 0.25 - 0.4 \text{ A} \\ \end{cases}$	-12%- 2% FS -18% - 2% FS		12% + 2% FS 18% + 2% FS	
t <sub>is_blank</sub>	Current Sense blanking time	Blanking time after current sense selection or driver activation	50		65	μS
t <sub>is</sub>	Current Sense settling time	0 V to FSR (full scale range)		230	265	μS

<sup>6.</sup> Kis trimmed at 150°C to higher value of spec range to be more centered over temp range.
7. Current sense output accuracy = Isout-Isout\_ideal relative to Isout\_ideal
8. FS (Full scale) = Ioutmax/Kis

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
DIGITAL INPUTS	CSB, SCLK, PWM1/2, SI					
Vinl	Input low level	V <sub>CC</sub> = 5 V			0.3·V <sub>CC</sub>	V
Vinh	Input high level		0.7·V <sub>CC</sub>			V
Vin_hyst	Input hysteresis		500			mV
Rcsb_pu	CSB pull-up resistor	V <sub>CC</sub> = 5 V <sub>CC</sub> 0 V < Vcsb < 0.7 · V <sub>CC</sub>	30	120	250	kΩ
Rsclk_pd	SCLK pull-down resistor	V <sub>CC</sub> = 5 V, Vsclk = 1.5 V	30	60	220	kΩ
Rsi_pd	SI pull-down resistor	V <sub>CC</sub> = 5 V, Vsi = 1.5 V	30	60	220	kΩ
Rpwm1_pd	PWM1 pull-down resistor	V <sub>CC</sub> = 5 V, Vpwm1 = 1.5 V	30	60	220	kΩ
Rpwm2_pd	PWM2 pull-down resistor	V <sub>CC</sub> = 5 V, Vpwm2 = 1.5 V, current sense disabled	30	60	220	kΩ
lleak_isout	Output leakage current	current sense enabled	-1		1	μΑ
Ccsb / sclk / pwm1/2	Pin capacitance	0 V < V <sub>CC</sub> < 5.25 V (Note 9)			10	pF
DIGITAL INPUTS	CSB, SCLK, SI; TIMING					
tsclk	Clock period	V <sub>CC</sub> = 5 V		1000		ns
tsclk_h	Clock high time		115			ns
tsclk_l	Clock low time		115			ns
tset_csb	CSB setup time, CSB low before rising edge of SCLK		400			ns
tset_sclk	SCLK setup time, SCLK low before rising edge of CSB		400			ns
tset_si	SI setup time		200			ns
thold_si	SI hold time		200			ns
tr_in	Rise time of input signal SI, SCLK, CSB				100	ns
tf_in	Fall time of input signal SI, SCLK, CSB				100	ns
tcsb_hi_stdby	Minimum CSB high time, switching from Standby mode	Transfer of SPI–command to input register, valid before tsact mode transition delay expires		5	10	μS
tcsb_hi_min	Minimum CSB high time, Active mode			2	4	μS

<sup>9.</sup> Values based on design and/or characterization.

# **ELECTRICAL CHARACTERISTICS** (continued)

 $4.5~V < V_{CC} < 5.25~V, 8~V < Vs < 18~V, -40 ^{\circ}C < T_{J} < 150 ^{\circ}C;$  unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
IGITAL OUTPUT	SO					
Vsol	Output low level	Iso = 5 mA			0.2·V <sub>CC</sub>	V
Vsoh	Output high level	Iso = -5 mA	0.8·V <sub>CC</sub>			V
lleak_so	Tristate leakage current	Vcsb = V <sub>CC</sub> , 0 V < Vso < V <sub>CC</sub>	-10		10	μΑ
Cso	Tristate input capacitance	Vcsb = V <sub>CC</sub> , 0 V < V <sub>CC</sub> < 5.25 V (Note 9)			10	pF
IGITAL OUTPUT	SO; TIMING					
tr_so	SO rise time	Cso = 100 pF		80	140	ns
tf_so	SO fall time	Cso = 100 pF		50	100	ns
ten_so_tril	SO enable time from tristate to low level	Cso = 100 pF, lload = 1 mA, pull-up load to V <sub>CC</sub>		100	250	ns
tdis_so_ltri	SO disable time from low level to tristate	Cso = 100 pF, lload = 4 mA, pull-up load to V <sub>CC</sub>		380	450	ns
ten_so_trih	SO enable time from tristate to high level	Cso = 100 pF, lload = -1 mA, pull-down load to GND		100	250	ns
tdis_so_htri	SO disable time from high level to tristate	Cso = 100 pF, lload = -4 mA, pull-down load to GND		450	ns	
td_so	SO delay time	$\begin{aligned} &\text{Vso} < 0.3 \cdot \text{V}_{CC}, \text{ or Vso} > 0.7 \cdot \text{V}_{CC}, \\ &\text{Cso} = 100 \text{ pF} \end{aligned}$		50	250	ns

9. Values based on design and/or characterization.

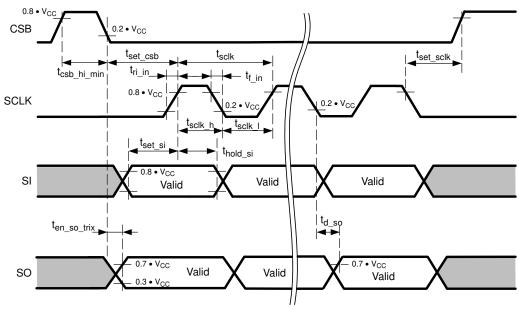


Figure 4. SPI Signals Timing Parameters

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
THERMAL PROTEC	CTION					
Tjtw_on	Temperature warning threshold	Junction temperature	140		160	°C
Tjtw_hys	Thermal warning hysteresis			5		°C
Tjsd_on	Thermal shutdown threshold, T <sub>J</sub> increasing	Junction temperature	160		180	°C
Tjsd_off	Thermal shutdown threshold, T <sub>J</sub> decreasing	Junction temperature	160			°C
Tjsd_hys	Thermal shutdown hysteresis			5		°C
Tjsdtw_delta	Temperature difference between warning and shutdown threshold			20		°C
td_tx	Filter time for thermal warning and shutdown	TW / TSD Global Status bits	10		100	μs
OPERATING MODE	S TIMING					
tact	Time delay for mode change from Unpowered mode into Standby mode	SPI communication ready after V <sub>CC</sub> reached V <sub>uv_VCC(off)</sub> threshold			30	μs
tsact	Time delay for mode change from Standby mode into Active mode	Time until output drivers are enabled after CSB going to high and CONTROL_0.MODE = 1		170	300	μs
tacts	Time delay for mode change from Active mode into Standby mode via SPI	Time until output drivers are disabled after CSB going to high and CONTROL_0.MODE = 0			300	μs
INTERNAL PWM C	ONTROL UNIT (OUT7 – OUT	10)				
PWMlo	PWM frequency, low selection	CONTROL_2.PWMI = 1, PWMx.FSELx = 0	135	170	190	Hz
PWMhi	PWM frequency, high selection	CONTROL_2.PWMI = 1, PWMx.FSELx = 1	175	225	250	Hz

#### **DETAILED OPERATING AND PIN DESCRIPTION**

#### General

The NCV7707/B provides six half-bridge drivers, five independent high-side outputs and a programmable PWM control unit for free configuration. Strict adherence to integrated circuit die temperature is necessary, with a static maximum die temperature of 150°C. This may limit the number of drivers enabled at one time. Output drive control and fault reporting are handled via the SPI (Serial Peripheral Interface) port. A SPI-controlled mode control provides a low quiescent sleep current mode when the device is not being utilized. A pull down is provided on the SI and SCLK inputs to ensure they default to a low state in the event of a severed input signal. A pull-up is provided on the CSB input disabling SPI communication in the event of an open CSB input.

## **Supply Concept**

### Power Supply Scheme - VS and VCC

The Vs power supply voltage is used to supply the half bridges and the high-side drivers. An all-internal chargepump is implemented to provide the gate-drive voltage for the n-channel type high-side transistors. The VCC voltage is used to supply the logic section of the IC, including the SPI interface.

Due to the independent logic supply voltage the control and status information will not be lost in case of a loss of Vs supply voltage. The device is designed to operate inside the specified parametric limits if the VCC supply voltage is within the specified voltage range (4.5 V to 5.25 V). Between the operational level and the VCC undervoltage threshold level (Vuv\_VCC) it is guaranteed that the device remains in a safe functional state without any inadvertent change to logic information.

### **Device / Module Ground Concept**

The high-side output stages OUT7-11 are designed to handle DC output voltage conditions down to -0.3 V and allow for short negative transient currents due to parasitic line inductances. Therefore the application has to take care that these ratings are not violated under abnormal operating conditions (module loss of GND, ground shift if load connected to external GND) by either implementing external bypass diodes connected to GND or a direct connection between load-GND and module-GND. Since these output stages are designed to drive resistive loads, restrictions on maximum inductance / clamping energy apply.

The heat slug is not hard—connected to internal GND rail. It has to be connected externally.

### Power Up/Down Control

In order to prevent uncontrolled operation of the device during power/up down, an undervoltage lockout feature is implemented. Both supply voltages (V<sub>CC</sub> and Vs) are

monitored for undervoltage conditions supporting a safe power—up transition. When Vs drops below the undervoltage threshold Vuv\_vs(off) (Vs undervoltage threshold) all output stages are switched to high—impedance state and the global status bit UOV\_OC is set. This bit is a multi information bit in the Global Status Byte which is set in case of overcurrent, Vs over— and undervoltage. In case of undervoltage the status bit STATUS\_2.VSUV is set, too.

Bit CONTROL\_3.OVUVR (Vs under-/overvoltage recovery behavior) can be used to select the desired recovery behavior after a Vs under-voltage event. In case of OVUVR = 0, all output stages return to their programmed state as soon as Vs recovers back to its normal operating range. If OVUVR is set, the automatic recovery function is disabled thus the output stages will remain in high-impedance condition until the status bits have been cleared by the microcontroller. To avoid high current oscillations in case of output short to GND and low Vs voltage conditions, it is recommended to disable the Vs-auto-recovery by setting OVUVR = 1.

#### Chargepump

In Standby mode, the chargepump is disabled. After enabling the device by setting bit CONTROL\_0.MODE to active (1), the internal oscillator is started and the voltage at the CHP output pin begins to increase. The output drivers are enabled after a delay of tsact once MODE was set to active.

## **Driver Outputs**

### **Output PWM Control**

For all half-bridge outputs as well as the high-side outputs the device features the possibility to logically combine the SPI-setting with a PWM signal that can be provided to the inputs PWM1 and ISOUT/PWM2, respectively. Each of the outputs has a fixed PWM signal assigned which is shown in Table 1. The PWM modulation is enabled by the respective bits in the control registers (CONTROL\_2.OUTx\_PWMx and CONTROL\_3.OUTx\_PWMx). In case of using pin ISOUT/PWM2, the application design has to take care of either disabling the current sense feature or to provide sufficient overdrive capability to maintain proper logic input levels for the PWM input.

In addition to the external signal control, all lighting outputs (OUT7–10) can also be PWM controlled via an internal PWM generator unit. While the PWM frequency can be individually selected between 170 Hz and 225 Hz thru bits PWMx.FSELx, the duty cycle can be programmed with 7–bits resolution PWMx.PW[6:0]. The selection between the different signal sources for these outputs is performed by programming bit CONTROL\_2.PWMI. Default value is 0 (external signal source). The general principle of the PWM generation control scheme is shown in Figure 5.

**Table 1. PWM CONTROL SCHEME** 

	PWM Cor	ntrol Input
Output	CONTROL_2.PWMI = 0	CONTROL_2.PWMI = 1
OUT1	PWM1	PWM1
OUT2	PWM1	PWM1
OUT3	PWM1	PWM1
OUT4	PWM1	PWM1
OUT5	ISOUT/PWM2	ISOUT/PWM2
OUT6	PWM1	PWM1
OUT7	PWM1	PWM_7/8.PW7[6:0]
OUT8	ISOUT/PWM2	PWM_7/8.PW8[6:0]
OUT9	PWM1	PWM_9/10.PW9[6:0]
OUT10	ISOUT/PWM2	PWM_9/10.PW10[6:0]
OUT11	PWM1	PWM1

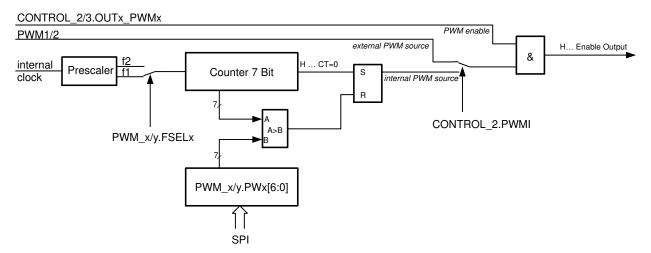


Figure 5. PWM Generation Diagram

### Programmable Soft-start Function to Drive Loads with Inrush Current Behavior

Loads with startup currents higher than the overcurrent limits (e.g. inrush current of bulbs, block current of motors and cold resistance of heaters) can be driven using the programmable soft-start function (Overcurrent auto-recovery mode). Each output driver provides a corresponding overcurrent recovery (CONTROL\_2/3.OCRx) to control the output behavior in case of a detected overcurrent event. If auto-recovery is enabled, the device automatically re-enables the output after a programmable recovery time. For all half-bridge outputs as well as the high-side outputs OUT9-11 and OUT7/8 in LED mode, the recovery frequency can be selected via SPI. OUT7/8 in bulb mode provides a fixed recovery frequency. The PWM modulated current will provide sufficient average current to power up the load (e.g. heat up the bulb) until the load reaches a steady state condition. The device itself cannot distinguish between a real overload and a non linear load like a bulb. Therefore a

real overload condition can only be qualified by time. It is recommended to only enable auto—recovery for a minimum amount of time to drive the connected load into a steady state condition. After turning off the auto—recovery function, the respective channel is automatically disabled if the overload condition still persists.

#### **Inductive Loads**

Each half bridge (OUT1-6) is built by internally connected low-side and high-side N-MOS transistors. Due to the built-in body diodes of the output transistors, inductive loads can be driven at the outputs without external free-wheeling diodes. The high-side drivers OUT7 to OUT11 are designed to drive resistive loads. Therefore only a limited clamping energy (W < 1 mJ) can be dissipated by the device. For inductive loads (L > 100  $\mu$ H) an external freewheeling diode connected between GND and the corresponding output is required.

The low-side driver at ECFB does not feature any freewheeling diode or clamping structure to handle inductive loads.

## **Current Sensing**

# Current Sense Output / PWM2 Input (Bidirectional Pin ISOUT/PWM2)

The current sense output allows a more precise analysis of the actual state of the load rather than the basic detection of an under—or overload condition. The sense output provides an image of the actual load current at the selected high side driver transistor. The current monitor function is available for all high current half—bridge outputs (OUT1, OUT4, OUT5 and OUT6), the high current high—side output (OUT11) as well as for the all bulb and LED outputs (OUT7–10).

The current sense ratio is fixed for the low resistance outputs OUT1/6/11 and OUT7/8 (bulb mode) to 1/10000, for door lock outputs OUT4/5 to 1/9200 and for the high ohmic outputs OUT9/10 and OUT7/8 (LED mode) to 1/2000. To prevent from false readouts, the signal at pin ISOUT is blanked after switching on the driver until correct settlement of the circuitry (max 65  $\mu$ s). Bits CONTROL\_3.IS[3:0] are used to select the output to be multiplexed to the current sense output.

The NCV7707/B provides a sample–and–hold functionality for the current sense output to enable precise and simple load current diagnostics even during PWM operation of the respective output. While in active high–side output state, the current provided at ISOUT reflects a (low–pass–filtered) image of the actual output current, the IS–output current is sampled and held constant as soon as the HS output transistor is commanded off via PWM (low–side or high–impedant on half–bridge outputs, high–impedant on HS–outputs). In case no previous current information is available in the Sample–and–hold stage (current sense channel changed while actual channel is commanded off) the sample stage is reset so that it reflects zero output current.

## **Electro Chromic Mirror**

### Controller for Electro-chromic Glass

The voltage of the electro-chromic element connected at pin ECFB can be controlled to a target value which is set by Control Register 1 (bits CONTROL\_1.DAC[5:0]). Setting bit CONTROL\_1.ECEN enables this function. At the same time OUT10 is enabled, regardless of its own control bit CONTROL\_1.HS10 and the respective PWM setting. An on-chip differential amplifier is used to control an external logic-level N-MOS pass device that delivers the power to

the electro–chromic element. The target voltage at ECFB is binary coded with a selectable full scale range (bit CONTROL\_2.FSR). The default clamping value for the output voltage (CONTROL\_2.FSR = 0) is 1.2 V, by setting CONTROL\_2.FSR to "1", the maximum output voltage is 1.5 V. The resolution of the DAC output voltage is independent of the full–scale–range selection.

The charging of the mirror (positive slope) is determined by the positive slew rate of the transconductance amplifier and the compensation capacitor, while in case of capacitive loads, the negative slope is mainly determined by the current consumption thru the load and its capacitance. To allow fast settling time changing from higher to lower output voltage values, the device provides two modes of operation:

- 1. Fast discharge: When the target output voltage is set to 0 V and bit CONTROL\_1.LS\_ECFB is set, the voltage at pin ECFB is pulled to ground by a 1.6 Ω low–side switch.
- PWM discharge: In case of PWM discharge being activated (CONFIG.ECM\_LSPWM = 1 and CONTROL\_1.LS\_ECFB = 1) (Figure 6):
  - a. The circuit regulation starts in normal regulation. The DAC value is turned to new lower value.
  - b. If the loop is detected out of regulation for a time longer than t\_rec (~3 ms), the ECON voltage is detected low (internal signal ECON\_LOW = 1), the regulator is switched off (DAC voltage at 0) and the fast discharge transistor is activated for ~300 ms (t\_disc). During this fast discharge, the ECON output is pulled low to prevent from shoot—thru currents.
  - c. At the end of the discharge pulse t\_disc the fast discharge is switched off and the regulation loop is activated again (with DAC to the correct wanted value), so the loop goes back to step b.) and the ECON\_LOW comparator is observed again. Before starting a discharge pulse, the ECLO and ECHI comparator data is latched.

The feedback loop out of regulation is monitored by comparing V(ECON) versus V(ECFB) and versus 400 mV. If the regulation is activated and ECON is below ECFB, or below 400 mV, then the loop is detected as out of regulation and internal signal ECON\_LOW is made 1. By activating the PWM discharge feature, the overcurrent recovery function is automatically disabled, regardless of the setting in CONTROL\_2.OCR\_ECFB.

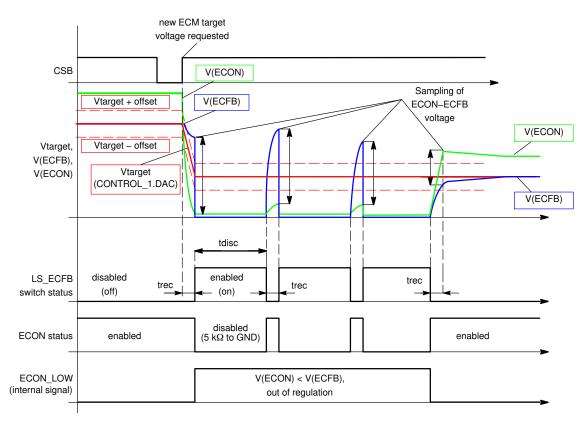


Figure 6. PWM Discharge Mode for ECFB

The controller provides a chip—internal diode from ECFB (Anode) to pin ECON (Cathode) to protect the external MOSFET. A capacitor of at least 4.7 nF has to be added to pin ECON for stability of the control loop. It is recommended to place 220 nF capacitor between ECFB and ground to increase the stability.

The status of the voltage control loop is reported via SPI. Bit STATUS\_2.ECHI = 1 indicates that the voltage on ECFB is higher than the programmed target value, STATUS\_2.ECLO = 1 indicates that the ECFB voltage is below the programmed value. Both status bits are valid if they are stable for at least 150  $\mu$ s (settling time of the

regulation loop). If PWM discharge is enabled (CONFIG.ECM\_LSPWM = 1), STATUS\_2.ECHI is latched at the end of the discharge cycle, therefore if set it indicates that the device is in active discharge operation.

Since OUT10 is the output of a high-side driver, it contains the same diagnostic functions as the other high-side drivers (e.g. switch-off during overcurrent condition). In electro-chrome mode, OUT10 can't be controlled by PWM. For noise immunity reasons, it is recommended to place the loop capacitors at ECON as well as another capacitor between ECFB and GND as close as possible to the respective pins.

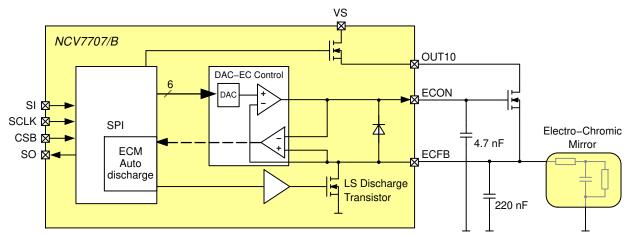


Figure 7. Electro Chromic Mirror Application Diagram

## **Diagnostic Functions**

All diagnostic functions (overcurrent, underload, power supply monitoring, thermal warning and thermal shutdown) are internally filtered. The failure condition has to be valid for the minimum specified filtering time (td old, td uld, td uvov and td tx) before the corresponding status bit in the status register is set. The filter function is used to improve the noise immunity of the device. The undercurrent and temperature warning functions are intended for information purpose and do not affect the state of the output drivers. An overcurrent condition disables the corresponding output driver while a thermal shutdown event disables all outputs into high impedance state. Depending on the setting of the overcurrent recovery bits in the input register, the driver can either perform an auto-retry or remain latched off until the microcontroller clears the corresponding status bits. Overtemperature shutdown is latch-off only, without auto-retry functionality.

## Overvoltage / Undervoltage Shutdown

If the supply voltage Vs rises above the switch off voltage Vov\_vs(off) or falls below Vuv\_vs(off), all output transistors are switched to high-impedance state and the global status bit UOV\_OC (multi information) is set. The status flag STATUS\_2.VSOV, resp. STATUS\_2.VSUV is set, too, to log the over-/under-voltage event. The bit CONTROL\_3.OVUVR can be used to determine the recovery behavior once the Vs supply voltage gets back into the specified nominal operating range. OVUVR = 0 enables auto-recovery, with OVUVR = 1 the output stages remain in high impedance condition until the status flags have been cleared. Once set, STATUS2.VSOV / VSUV can only be reset by a read&clear access to the status register STATUS\_2.

#### Thermal Warning and Overtemperature Shutdown

The device provides a dual-stage overtemperature protection. If the junction temperature rises above Tjtw\_on, a temperature warning flag (TW) is set in the Global Status Byte and can be read via SPI. The control software can then react onto this overload condition by a controlled disable of individual outputs. If however the junction temperature reaches the second threshold Tjsd\_on, the thermal shutdown bit TSD is set in the Global Status Byte and all output stages are switched into high impedance state to protect the device. The minimum shutdown delay for overtemperature is td\_tx. The output channels can be re-enabled after the device cooled down and the TSD flag has been reset by the microcontroller by setting CONTROL\_0.MODE = 0.

#### Openload (Underload) Detection

The openload detection monitors the load current in the output stage while the transistor is active. If the load current is below the openload detection threshold for at least td\_uld, the corresponding bit (ULDx) is set in the status registers STATUS\_1/2. The status of the output remains unchanged. Once set, ULDx remains set regardless of the actual load condition. It has to be reset by a read&write access to the corresponding status register.

#### **Overload Detection**

An overcurrent condition is indicated by the flag (UOV\_OC) in the Global Status Byte after a filter time of at least td\_old. The channel dependent overcurrent flags are set in the status registers (STATUS\_0/2.OCx) and the corresponding driver is switched into high impedance state to protect the device. Each low-side and high-side driver stage provides its own overcurrent flag. Resetting this overcurrent flag automatically re-enables the respective output (provided it is still enabled thru the Control register). If the over current recovery function is enabled, the internal chip logic automatically resets the overcurrent flag after a fixed delay time, generating a PWM modulated current with a programmable duty cycle. Otherwise the status bits have to be cleared by the microcontroller by a read&clear access to the corresponding status register.

#### **Cross-current Protection**

All six half-bridges are protected against cross-currents by internal circuitry. If one driver is turned off (LS or HS), the activation of the other driver of the same output will be automatically delayed by the cross current protection mechanism until the active driver is safely turned off.

#### **Mode Control**

## Wake-up and Mode Control

Two different modes are available:

- Active mode
- Standby mode

After power-up of VCC the device starts in Standby mode. Pulling the chip-select signal CSB to low level causes the device to change into Active mode (analog part active).

After at least 10  $\mu$ s delay, the first SPI communication is valid and bit CONTROL\_0.MODE can be used to set the desired mode of operation. If bit MODE remains reset (0), the device returns to the Standby mode after an internal delay of max. 8  $\mu$ s, clearing all register content and setting all output stages into high impedance state.

#### VCC Power-up Delay (tact) Output stages Hi-Z Delay (tsact) MODE = 1 SPI not read MODE = 1 CSB = 0 CSB = 0CSB = 1 and MODE = 0 Standby Active Output stages High-Z CSB = 0MODF = 0Delay timer and expired CSB = 1 Delay (tacts) Output stages control thru output registers Register content val

Figure 8. Mode Transitions Diagram

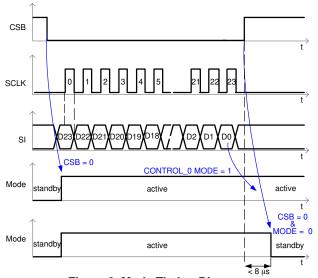


Figure 9. Mode Timing Diagram

#### **SPI Control**

## **General Description**

The 4-wire SPI interface establishes a full duplex synchronous serial communication link between the NCV7707/B and the application's microcontroller. The NCV7707/B always operates in slave mode whereas the controller provides the master function. A SPI access is performed by applying an active-low slave select signal at CSB. SI is the data input, SO the data output. The SPI master provides the clock to the NCV7707/B via the SCLK input. The digital input data is sampled at the rising edge at SCLK. The data output SO is in high impedance state (tri–state) when CSB is high. To readout the global error flag without sending a complete SPI frame, SO indicates the corresponding value as soon as CSB is set to active. With the first rising edge at SCLK after the high-to-low transition of CSB, the content of the selected register is transferred into the output shift register.

The NCV7707/B provides four control registers (CONTROL 0/1/2/3), two PWM configuration registers (PWM\_7/8 and PWM\_9/10), three status registers (STATUS\_0/1/2) and one general configuration register (CONFIG). Each of these register contains 16-bit data, together with the 8-bit frame header (access type, register address), the SPI frame length is therefore 24 bits. In addition to the read/write accessible registers, the 8-bit NCV7707/B provides five ID (ID\_HEADER, ID\_VERSION, ID\_CODE1/2 ID\_SPI-FRAME) with 8-bit data length. The content of these registers can still be read out by a 24-bit access, the data is then transferred in the MSB section of the data frame.

## **SPI Frame Format**

Figure 10 shows the general format of the NCV7707/B SPI frame.

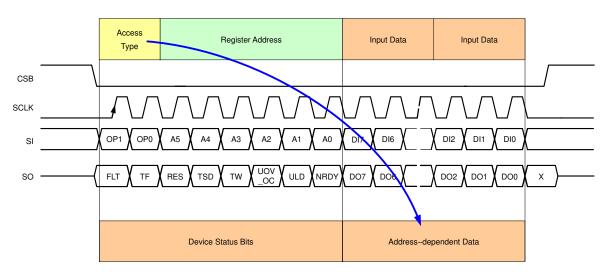


Figure 10. SPI Frame Format

#### 24-bit SPI Interface

Both 24-bit input and output data are MSB first. Each SPI-input frame consists of a command byte followed by two data bytes. The data returned on SO within the same frame always starts with the global status byte. It provides general status information about the device. It is then followed by 2 data bytes (in-frame response) which content depends on the information transmitted in the command byte. For write access cycles, the global status byte is followed by the previous content of the addressed register.

#### Chip Select Bar (CSB)

CSB is the SPI input pin which controls the data transfer of the device. When CSB is high, no data transfer is possible and the output pin SO is set to high impedance. If CSB goes low, the serial data transfer is allowed and can be started. The communication ends when CSB goes high again.

### Serial Clock (SCLK)

If CSB is set to low, the communication starts with the rising edge of the SCLK input pin. At each rising edge of SCLK, the data at the input pin Serial IN (SI) is latched. The data is shifted out thru the data output pin SO after the falling edges of SCLK. The clock SCLK must be active only within the frame time, means when CSB is low. The correct transmission is monitored by counting the number of clock pulses during the communication frame. If the number of SCLK pulses does not correspond to the frame width indicated in the SPI-frame-ID (Chip ID Register, address 3Eh) the frame will be ignored and the communication failure bit "TF" in the global status byte will be set. Due to this safety functionality, daisy chaining the SPI is not possible. Instead, a parallel operation of the SPI bus by controlling the CSB signal of the connected ICs is recommended.

## Serial Data In (SI)

During the rising edges of SCLK (CSB is low), the data is transferred into the device thru the input pin SI in a serial

way. The device features a stuck-at-one detection, thus upon detection of a command = FFFFFFh, the device will be forced into the Standby mode. All output drivers are switched off.

### Serial Data Out (SO)

The SO data output driver is activated by a logical low level at the CSB input and will go from high impedance to a low or high level depending on the global status bit, FLT (Global Error Flag). The first rising edge of the SCLK input after a high to low transition of the CSB pin will transfer the content of the selected register into the data out shift register. Each subsequent falling edge of the SCLK will shift the next bit thru SO out of the device.

#### Command Byte / Global Status Byte

Each communication frame starts with a command byte (Table 2). It consists of an operation code (OP[1:0], Table 3) which specifies the type of operation (Read, Write, Read & Clear, Readout Device Information) and a six bit address (A[5:0], Table 4). If less than six address bits are required, the remaining bits are unused but are reserved. Both Write and Read mode allow access to the internal registers of the device. A "Read & Clear"–access is used to read a status register and subsequently clear its content. The "Read Device Information" allows to read out device related information such as ID–Header, Product Code, Silicon Version and Category and the SPI–frame ID. While receiving the command byte, the global status byte is transmitted to the microcontroller. It contains global fault information for the device, as shown in Table 6.

# **ID Register**

Chip ID Information is stored in five special 8-bit ID registers (Table 5). The content can be read out at the beginning of the communication.

Table 2	COMMAND	DVTE /	CLOBAL	SILLATO	DVTE CT	DIICTLIDE

		Command Byte (IN) / Global Status Byte (OUT)						
Bit	23	22	21	20	19	18	17	16
NCV7707 IN	OP1	OP0	A5	A4	A3	A2	A1	A0
NCV7707 OUT	FLT	TF	RESB	TSD	TW	UOV_OC	ULD	NRDY
Reset Value	1	0	0	0	0	0	0	1

Table 3. COMMAND BYTE, ACCESS MODE

OP1	OP0	Description
0	0	Write Access (W)
0	1	Read Access (R)
1	0	Read and Clear Access (RC)
1	1	Read Device ID (RDID)

Table 4. COMMAND BYTE, REGISTER ADDRESS

A[5:0]	Access	Description	Content
00h	R/W	Control Register CONTROL_0	Device mode control, Bridge outputs control
01h	R/W	Control Register CONTROL_1	High-side outputs control, ECM control
02h	R/W	Control Register CONTROL_2	Bridge outputs recovery control, PWM enable, ECM setup
03h	R/W	Control Register CONTROL_3	High-side outputs recovery control, PWM enable, Current Sense selection
08h	R/W	PWM Control Register PWM_7/8	PWM control register for OUT7,8
09h	R/W	PWM Control Register PWM_9/10	PWM control register for OUT9,10
10h	R/RC	Status Register STATUS_0	Bridge outputs Overcurrent diagnosis
11h	R/RC	Status Register STATUS_1	Bridge outputs Underload diagnosis
12h	R/RC	Status Register STATUS_2	HS outputs Overcurrent and Underload diagnosis, Vs Over- and Undervoltage, EC-mirror
3Fh	R/W	Configuration Register CONFIG	Mask bits for global fault bits

# **Table 5. CHIP ID INFORMATION**

A[5:0]	Access	Description	Content
00h	RDID	ID header	4300h
01h	RDID	Version	0400h (NCV7707) 0500h (NCV7707B)
02h	RDID	Product Code 1	7700h
03h	RDID	Product Code 2	0700h
3Eh	RDID	SPI-Frame ID	0200h